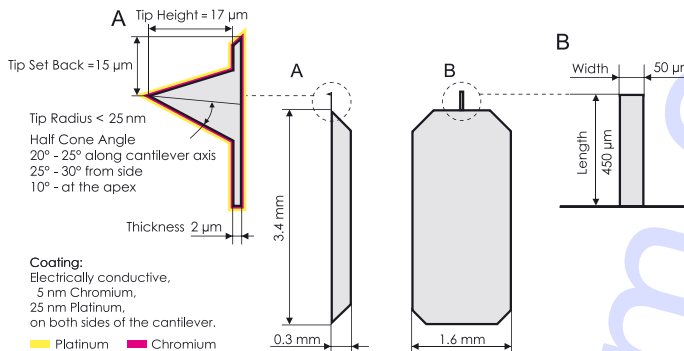




## AFM probe Model: **ElectriCont**



- Contact Mode and Electric Modes like:
  - Scanning Capacitance Microscopy (SCM)
  - Electrostatic Force Microscopy (EFM)
  - Kelvin probe Force Microscopy (KFM)
  - Scanning probe lithography
- Rotated Monolithic Silicon Probe  
Symmetric Tip Shape  
Chipsize: 3.4 x 1.6 x 0.3 mm



- Coating: Electrically conductive coating of 5 nm Chromium and 25 nm Platinum on both sides of the cantilever. This coating also enhances the laser reflectivity of the cantilever
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.

	Typical Values	Range
<b>Resonant Frequency</b>	13 kHz	+/- 4 kHz
<b>Force Constant</b>	0.2 N/m	0.07 - 0.4 N/m
<b>Cantilever Length</b>	450 $\mu\text{m}$	+/- 10 $\mu\text{m}$
<b>Mean Width</b>	50 $\mu\text{m}$	+/- 5 $\mu\text{m}$
<b>Thickness</b>	2 $\mu\text{m}$	+/- 1 $\mu\text{m}$
<b>Tip Height</b>	17 $\mu\text{m}$	+/- 2 $\mu\text{m}$
<b>Tip Set Back</b>	15 $\mu\text{m}$	+/- 5 $\mu\text{m}$
<b>Tip Radius</b>	< 25 nm	
<b>Coating</b>	Cr/Pt on both sides	
<b>Half Cone Angle</b>	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	
<b>Contact Resistance</b>	300 Ohms on platinum thin film surface	

Order Code	Units in Package	Coating	Price
ContE-10	10 pieces	Cr/Pt	\$240
ContE-50	50 pieces	Cr/Pt	\$1000